## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re P	atent A	pplica	ation of:			
Sang-l	Hyub Ll	EE				
Applica	ation N	0.:		Group Art Unit:		
Filed:	December 16, 2003			Examiner:		
For:	FLYIN	IG HE	IGHT MEASUREMENT METHO	DD AND SYSTEM		
			INFORMATION DISCLOS	SURE STATEMENT		
РО Во	x 1450		Patents 13-1450			
Sir:						
subjec	ed certa t U.S. p	ain info atent	ormation which the Examiner ma	ovisions of 37 CFR § 1.56, there is hereby ay consider material to the examination of the the Examiner make this information of record bject application.		
	1.	Encl	osures accompanying this Inforr	nation Disclosure Statement are:		
	1b. 1c. 1d.		application or a PCT Internation English language translation (deach non-English language pu Explanations of Relevancy of F	complete or relevant portion(s)) attached to		
	2. 🗌			a concise explanation of what is presently each non-English language publication is		
	2a.		enclosed "English-language ve indicates the degree of relevan 609, Minimum Requirements for	s 2a, 2b, 2c and/or 2d) sh language publications were cited on the ersion of the search report or action which are found by the foreign office". (See MPEP or an Information Disclosure Statement, Part selevance, pp. 600-100 to 600-101, Rev. 1,		
	2b.		set forth in the application.			

	2c.   2d.		d to each non	uage translation (complete -English language publica eto.	
3.	to be, ma (other the	aterial to patentability an search report(s) fro	nor a represe om a counterp	cited in this Statement is, on the number of	been made a PCT
			Respe	ectfully submitted,	
			STAAS	S & HALSEY LLP	
Dated: D	ecember	16, 2003	Ву:	Mula DSE	
1201 New Washingto Telephone Facsimile:	on, D.C. 2 e: (202) 43	34-1500		Michael D. Stein Registration No. 37,240	

FORM PTO-1449

#### U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

1793.1067
ATTORNEY DOCKET NO.

APPLICATION NO.

# LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

1793.1067	
IRST NAMED INVENTOR	
Sang-Hyub LEE	
FILING DATE	GROUP ART UNIT

### **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
/M.B./	AA	5,880,899	3/9/1999	Blachek, et al.			2/25/1997
	AB						
	AC						
	AD						
	AE						
	AF						

### **FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLAT YES N	10 10
/M.B./	AG	6-215514	8/5/1994	Japan			Abstract	
	АН							
	AI							
	AJ							
	AK							
	AL							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

AM	_				
AN					
 AO		,			_

EXAMINER /Mark Blouin/	DATE CONSIDERED 03/25/2009
EXAMINER: Initial if reference considered, whether or not citation is in confor and not considered. Include copy of this form with next communication to app	